

INTERNATIONAL BIOMETRIC PERFORMANCE CONFERENCE

Evaluation and Performance of Biometric Technologies







NIST, NPL and Fraunhofer IGD invite talks for the IBPC conference on performance and testing of biometric systems. The forum will bring together evaluators, users, technology providers to discuss performance in applications that embed biometric functions or component. The conference aims to detail developments in *how* systems are being tested, certified, upgraded and improved rather than to snapshot specific testing results. The conference specifically invites talks on Automated Border Control, a rapidly growing application of front-end and back-end biometric technology today, and emerging biometric uses. The talks will target operationally relevant themes, and will give emphasis to design, procurement, and what operators require from test and evaluation activities. The conference aims to advance future use of biometrics by sifting salient points from the accumulated experience of the last decade, to identify novel evaluation methodologies and recent trends in testing, and to determine what is most operationally relevant in the context of the contemporary and emerging marketplaces.

Topic area I: Test methods:

Identification systems: metrics, limits, scalability

Product vs. component tests, certification, interoperability

Beyond the DET: Novel tests and performance metrics

Efficient testing, re-usable testing, frameworks

Statistical methods for efficiency, for prediction

Desirable, undesirable algorithm properties – 1:1, 1:N and forensics

Desirable, undesirable sample properties – Level III Conformance tests

Quality and reliability of sensors and capture devices

Untested and unspoken aspects of performance: what matters, what

does not, what's in the noise?

Testing and standardization gaps

Usability / Accessibility testing for biometrics

Topic area II: Operational aspects

Certification criteria and certification programs

How to drive error rates lower: Measurement for control + mitigation

New testing campaigns

Total system performance and tradeoffs: Accuracy, speed, security, reliability, usability, interoperability, scalability, assurance, stability

How to specify performance (for procurement)

Technology vs. scenario vs. operational vs. other tests

From research, to design, to deployment, to fielded operation

Quality of samples and databases. Evaluation / roles of Quality

Remote testing; testing in the cloud; data in the cloud.

Data and its ground-truth: operational vs. laboratory vs. synthetic

Topics area III: Security and privacy aspects

Evaluation of multi-factor authentication

Template protection and biometric pseudo-identifiers

Privacy enhancing technology, de-identification

Remote authentication: Challenges, assurance, testing

Resilience under active attacks (vulnerability, spoofing)

Defeat of systems (detection of evasion)

Feasibility of common criteria testing of biometric components

Retrospectives, lessons learned, long term perspective, critical appraisal

of other programs, events, specifications.

Program Committee:

Patrick Grother, Elham Tabassi, NIST, US

Tony Mansfield, NPL, UK

Christoph Busch, Fraunhofer IGD, DE

Intended speakers:

Research and development staff, system analysts, Users, evaluators, planners, writers of technical specifications, standards developers and adopters.

Target audience:

Professionals concerned with biometric system evaluation, procurement, deployment, maintenance, design, configuration, integration, standardization, research and development.

Important dates:

Jan 11 2012	Submission of abstracts
Jan 15 2012	Notification of acceptance
Feb 17 2012	Submission of presentation and supporting papers
Mar 05 2012	Satellite Workshops I NFIQ 2.0 + Others, TBA
Mar 06 2012	IBPC 2012 Conference
Mar 06 2012 Mar 08 2012	IBPC 2012 Conference

Logistics:

When: March 5-9, 2012

Where: Green Auditorium (cap. 250)

NIST Gaithersburg, MD, USA

Internet: Wireless

Hotel: Two Gaithersburg Area Hotels, TBA

Fee: \$US 175 via Registration

Contact the organizers:

Email: ibpc2012 AT nist DOT gov





